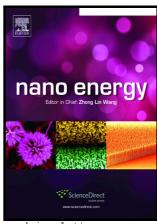
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www.elsevier.com/locate/nanoenergy

PII: S2211-2855(18)30528-7

DOI: https://doi.org/10.1016/j.nanoen.2018.07.040

Reference: NANOEN2907

To appear in: Nano Energy

Received date: 10 June 2018 Revised date: 3 July 2018 Accepted date: 20 July 2018

Cite this article as: Ik Kyeong Jin, Jun-Young Park, Byung-Hyun Lee, Seung-Bae Jeon, Il-Woong Tcho, Sang-Jae Park, Weon-Guk Kim, Joon-Kyu Han, Seung-Wook Lee, Seong-Yeon Kim, Hagyoul Bae, Daewon Kim and Yang-Kyu Choi, Self-Powered Data Erasing of Nanoscale Flash Memory by Triboelectricity, *Nano Energy*, https://doi.org/10.1016/j.nanoen.2018.07.040

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### ACCEPTED MANUSCRIPT

# Self-Powered Data Erasing of Nanoscale Flash Memory by Triboelectricity

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